

Notic	of	References	Cit	d
-------	----	------------	-----	---

1			
Application/Control No. 10/056,935	Applicant(s)/Patent Under Reexamination		
	COWLES ET AL		
Examiner	Art Unit		
Hien N Nauven	2824	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,014,340	01-2000	Sawada, Seiji	365/233
*	В	US-6,233,195	05-2001	Yamazaki et al.	365/230.03
*	С	US-6,339,552	01-2002	Taruishi et al.	365/189.05
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	н	US-			
	ı	US-		(+)	•
	J	US-			
	К	US-			,
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	σ					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.